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AMPLIFIER APPLICATIONS GUIDE

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1992 AMPLIFIER APPLICATIONS GUIDE

First Printing Errata Sheet



1992 Amplifier Applications Guide

First Printing Errata Sheet-August, 1992

Front Cover, Top diagram: Remove short between pin 6 and pin 2 of AD843 and replace with a capacitor.

Front Cover, Bottom diagram: Pin 13 of U2 should be labeled: +5V.

Back Cover, Top diagram: Remove short between pin 6 and pin 2. Replace with a capacitor. Reverse positions of $2.2\mu F$ and $0.1\mu F$ capacitors.

Back Cover, Bottom diagram: Reverse the polarity of the inputs to U3A.

Copyright Page: "Herin" should be spelled "Herein"

Outline section: Under SECTION II outline, under the third bullet point, add "Monolithic Thermocouple Amplifiers" after "Thermistors".

Outline section: Under SECTION XI outline, change "Effect" to "Affect".

Figure 1.1: Add OP-295 to list of Low Power, Single Supply Amplifiers

Figure 1.2: Change OP27 to OP275, Add OP27 between AD624 and AD829

Figure 1.4: Add label "VIDEO" to section below "PROFESSIONAL VIDEO"

Figure 1.6: Add AD844 between OP-160 and AD811 in middle of diagram.

Figure 1.7: Add OP-275 dot above AD811 dot between AD9630 and AD9620

Outline Page, Section II: add "Monolithic Thermocouple Amplifiers" after Thermistors in outline.

Figure 2.10: Pin 3 of second OP-177 should go to ground.

Figure 2.21: Make "-" sign on first op amp horizontal.

Figure 2.22: Remove "1%" label from 499Ω resistor and $27.4k\Omega$ resistor.

Figure 2.23: Remove the erroneous "10" below Vout. Remove "1%" label from 475Ω resistor.

Figure 2.26: Second column total error should be 116, third column should be 112, and fourth column should be 280.

Figure 2.29: Re-label S1, S2, S3, S4 as SW1, SW2, SW3, SW4 to be consistent with the text.

Figure 2.31: Add comment ... "and low peak-to-peak voltage noise in 0.1 to 10Hz bandwidth" to first bullet point.

Figure 2.34: Change 1000 to 100 on horizontal scale of left-hand graph of voltage noise.

Figure 2.35: Remove "Ultra" from title and first bullet point. Change Hz in first and third bullet points to $\sqrt{\text{Hz}}$.

Figure 2.38: Change title to "Choosing Instrumentation Amplifiers".

Page 2.28: In second paragraph, change "Bifet" to "Super-Beta".

Figure 2.42: Title of first column should be "Gain Accuracy". Title of fourth column should be: CMRR dB @ 60Hz. In title of fifth column change hZ to Hz.

Figure 2.43: For Single Supply chart, change CMRR dB to CMRR dB @60Hz. In "Input-Overvoltage Protected" chart, add AD626 with +54V Max Input Voltage.

Figure 2.44: Change Gain Accuracy of AD626 to 0.5. Change title of last column to CMRR, dB @ 60Hz.

Figure 2.45: Remove AD526 from selection table! It is not an instrumentation amplifier!!!

Figure 2.47: Change fifth bullet point to show +5 to $\pm 15\text{V}$ specified supply range.

Figure 2.51: Add G=1000, and "Scope Synchronized to Chopper Frequency" to diagram.

Figure 2.52: Add "Scope Unsynchronized" to diagram.

Figure 2.53: Add "Scope Unsynchronized" to diagram.

Page 2.40: First column, line 12 should read: "When compared to other temperature sensors, thermocouples are quite linear. However, their low....."

Figure 2.60: AD592 should be shown as a current source.

Figure 2.61: AD592 should be shown as a current source. Label amplifiers from left to right: A1, A2, A3 since this is mentioned in text.

Page 2.59: In first paragraph, $0.5^\circ\text{C}/\text{mW}$ should be $0.5^\circ\text{C}/\text{W}$.

Figure 2.67: "Guage" in title should be spelled "Gauge".

Figure 2.68: Drawn to show Kelvin connection better.

Page 2.68 2.69: Add section titled: "Monolithic Thermocouple Amplifiers with Cold Junction Compensation: The AD594/AD595/AD596/AD597. This is an extraction of the introductory remarks on the respective data sheets. **Complete text is attached to this Errata sheet.**

Figure 3.2: Ideal diode should be in parallel with photo current generator not in series.

Figure 3.9: Label the IC pin connect to the standoff as "Bent Lead".

Figure 3.16: Add pin numbers corresponding to AD645 pinouts. Show main amplifier connected to collector of current mirror. Output of amplifier goes to pin 6. (**Diagram attached to this errata sheet**).

Figure 3.18: Delete resistor network connected to bottom of $1000M\Omega$ summing resistor. Connect bottom of $1000M\Omega$ resistor to a 100Ω resistor connected to ground. Connect a $1M\Omega$ resistor to the junction of the 100Ω and $1000M\Omega$ resistor. The other end of the $1M\Omega$ resistor should go to the wiper of a $100k\Omega$ pot which is connected between + and - 15V. (**Diagram attached to this errata sheet**).

Figure 3.19: Delete R_p . Change $1000M\Omega$ resistor to $R_p = 15.4M\Omega$. Connect bottom of $15.4M\Omega$ resistor to a 100Ω resistor which goes to ground. Connect a $1M\Omega$ resistor to the junction of the $100M\Omega$ and $15.4M\Omega$ resistor. The other end of the $1M\Omega$ resistor should go to the wiper of a $100k\Omega$ pot which is connected between + and - 15V. (**Diagram attached to this errata sheet**.)

Figure 3.21: Same correction as Figure 3.19.
(Diagram attached to this errata sheet).

Figure 3.24: Same correction as Figure 3.19.
(Diagram attached to this errata sheet).

Figure 3.28: In diagram, C_2 should be $50pF$, not $10pF$.

Figure 3.30: " In^+ " in second term of long equation for V_{on} should be squared.

Figure 3.37: Same correction as Figure 3.19.
(Diagram attached to this errata sheet.)

Page 3.31: Second column, lines 5 and 6: "6" should be "5.6".
Second column, line 13, $\sqrt{2}$ should be $\sqrt{10}$.

Figure 3.41: R_4 should be $900k\Omega$. Equation on left-hand side should read:

WITH "T" NETWORK: $\frac{1}{\beta_T} = (1 + \frac{100}{1000})(1 + \frac{900}{100})$
 $= (1.1)(10) = 11.1$

$$\frac{1/\beta_T}{1/\beta_1} = 5.6$$

Figure 3.48: Change third bullet point to read: "Minimize op amp input capacitance: $C_{in} \leq C_d$."

Page 4.1: Add John Wynne, Faisal Ansari, Joe Buxton, Adolfo Garcia, and Steve Sockolov to the list of authors.

Figure 4.4: Reverse the polarity of the inputs of A2.

Page 4.5: Column 2, line 23: Change "goes" to "go".

Page 4.9: Last sentence: Change "control" to "compression".

Page 4.10: Last paragraph: "N-Channel" should be "P-Channel".

Figure 4.10: Add (A) to left-hand drawing and (B) to right-hand drawing.

Page 4.13: First column, line 11: Change "4.8(b)" to "4.10(b)".

Page 4.13: Second paragraph: "Figure 4.8(b)" should be "Figure 4.10(b)".

Figure 4.11: Delete "-5V". Connect bottom of this $10k\Omega$ resistor to V- of the op amp.

Figure 4.15: Change $121k\Omega$ resistor to $12.1k\Omega$.

Figure 4.16: Change offset voltage to $300\mu V$ max, Change supply current to $300\mu A$ max, change gain-bandwidth product to $85kHz$.

Figure 4.17: Reverse the polarity of the inputs to the OP-295.

Figure 4.18: Reverse the polarity of the inputs to the OP-295.

Page 4.21: Upper right-hand paragraph should read "The amplifier is frequency compensated so that it can drive a $1\mu F$ to $10\mu F$ output capacitance without oscillation."

Page 4.21: Middle right-hand paragraph should read; "The OP-90/OP-290/OP-490 comes close to"

Figure 4.19: Change specs on OP-295 as follows: Max Vos = 300 μ V, Max Is/Amplifier = 150 μ A.

Add data for dual OP-213 into table as follows

Dual	OP-213	150 μ V	0.2 μ V/C	2mA
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Figure 4.24: Reverse polarity of the inputs of the OP-27.

Page 4.31: Second column , line 1 should read: "...a few inches of conductor can have...."

Page 4.34: Add Reference: Fair-Rite Products, P.O. Box J, Wallkill, NY, 12589

Figure 4.31: Top trace is 100mV/div., Bottom trace is 5mV/div.

Figure 5.4: Invert the polarity of the inputs to U1.

Page 5.10: Second column, line 5: Change R4 to R2.

Figure 5.9: In diagram, change R3 to R1, R4 to R2, R1 to R3, and R2 to R4.

In table, change R1,R2 to R1,R3 and R3,R4 to R2,R4. Change 12k Ω under R2,R4 for SSM-2143 to 6k Ω .

Figure 5.16: Change arrows to grounds.

Figure 5.18: Change equation for Gain to GAIN = 1 + R1/R2

Page 5.22: Add Reference 3: Aavid Engineering Co., P.O. Box 400, Laconia, NH, 03247.

Page 6.19: Line 15 should read: ..." Furthermore, its success will still be limited by the number of parts that.....".

Page 6.21: Second column, line 15 should read: ..."They exist between....."

Figure 7.8: Change SFDR to 110 dBc.

Page 7.7: "Figure 710" in right-hand column should be "Figure 7.10".

Page 7.12: Last paragraph, third sentence should read: "The percentage change in closed loop gain, ΔA_{CL} , for a percentage change in open loop gain, ΔA , is approximately $\Delta A / |A_0 \beta|$, where A_0 is the nominal dc open loop gain at room temperature."

Figure 7.16: Change second bullet point to read: "Percentage Change in Open Loop Gain", and fifth bullet point to read: "Percentage Change in Closed Loop Gain".

Figure 7.27: Substitute curves from Figure 8.20. Table for Gain, BW, and Product remains the same.

Figure 7.85: Change $5.1\text{k}\Omega$ resistors to $5.62\text{k}\Omega$. Change top $16\text{k}\Omega$ resistor to $5.76\text{k}\Omega$. Parallel it with a 100pF capacitor. Change bottom $16\text{k}\Omega$ resistor to $5.49\text{k}\Omega$. Parallel it with a 100pF capacitor. Change 270Ω resistors to 51Ω . Change differentially connected $0.01\mu\text{F}$ capacitor to $0.0047\mu\text{F}$. Eliminate 120Ω resistors to ground. Label top input to AD1879 "-IN" and bottom input "+IN". (**Diagram attached to errata sheet**).

Page 7.61: First column: Change last sentence to read: "The differentially connected $0.0047\mu\text{F}$ capacitor supplies most of the differential-mode transient currents, while the $0.01\mu\text{F}$ capacitors connected to ground absorb spike currents which are common mode. The 51Ω series....."

Figure 8.20: First graph should be INVERTING FREQUENCY RESPONSE. Settling time photo should be the same as Figure 7.32.

Page 8.29: First column, line 19: "bully" should be "bulky".

Figure 8.36: R2 in the denominator of the equation for I_L should be changed to R4.

Figure 8.37: Reverse the input polarities for both AD9617s.

Figure 8.42: Show termination resistor between pins 1 and 2 of AD830. Do not connect to ground at AD830.

Page 9.19: Right-hand side of Equation 9.2.5 should be positive.

Figure 9.2.6: Change title to VCA WITH SQUARE LAW GAIN CONTROL USING THE AD539 MULTIPLIER. Input range should be 50dB , not 55dB .

Figure 9.2.11: Change " R_F " to " $R8 = R9$ "

Page 9.38: Line 5 in first paragraph under 9.2.5: C1 should be C4.

Figure 9.2.25: First label on horizontal axis should be 0.1.

Figure 9.2.26: Extend horizontal axis back one decade to $100\mu\text{V}$. The graph is basically flat back to this point.

Figure 9.2.28: Change label on vertical axis to mV RMS

Figure 9.2.29: Change vertical axis scale to Volts.

Page 9.51: Line 5 under 9.2.9: "increases" should be "decreases".

Page 9.71: Second paragraph, line 5: +100mV should be -100mV.

Page 9.72: The right-hand term of Eq. 9.3.24 should be negative. The phrase:"that is, a small *forward*-bias on the collector." should immediately follow the equation.

Page 9.82: In Eq. 9.4.13 the term " A^{N-1} " in the last fraction should be moved to the left under $E\sqrt{A}$.

Page 9.86: In first equation, N-2 should be N-1. In Eq. 9.4.20, N-2 should be N-1. In Eq. 9.4.22, N-3 should be N-2. In the sentence between Eq. 9.4.22 and Eq. 9.4.23, 6.6438 should be 6.6435.

Figure 9.4.9: Delete "(NOT USED)" from output of last stage.

Figure 9.4.11: Add load resistor R_Y to ground.

Page 9.91: In Eq. 9.4.39, and 9.4.40 change + to - after the number "1".

Page 9.100: Change title to "Some Aspects of Log-Amps Based on Bipolar Differential Stages".

Page 10.3: Second column, line 7: "cascade" should be "cascode".

Page 10.15: Second column, line 9: Change generation to degeneration.

Page 10.27: First column, line 5: change "transistor" to "resistor".

Figure 10.34: Change "BIFET" to "BIFET and PNP Input" for both bullet points.

Section 11 Title Sheet: Change "Effect" to "Affect"

Figure 11.7: For AD712, Change series resistor to $14k\Omega$ and noise to $22nV/\sqrt{Hz}$

Page 11.11: In title, change "Effect" to "Affect".

Page 11.23: Last line of second column should read: " $1nV/\sqrt{Hz}$ in the best low noise op amps."

Page 11.26: First line should read: "If the impedance is resistive there is a..."

Figure 11.34: In equation F, change non-inverting to inverting.

Figure 11.35: RTI NOISE should be nV/\sqrt{Hz} .

Figure 11.36: Right-hand top graph should be for $R_s = 10k\Omega$.

Figure 11.56: Allow space between "Conduction" and "Electrostatic", and space between "Induction" and "Electromagnetic".

Figure 11.58: Add low and high frequency decoupling capacitors to left-hand node.
Remove connecting line between A and B in right-hand diagram.

Page 11.56: First column, line 15: insert the word "formula" after the word "reactance".

Page 11.58: Second column: Change last sentence to read: "If sensitive circuitry is located close to a switching supply, its performance may be devastated - if it is further away problems will be minimized."

Figure 12.28: Insert space between "Mount" and "adhesive" on next to last line.

Page 12.26: Change Wainwright address to: Wainwright Instruments Inc., 7770 Regents Rd., #113, Suite 371, San Diego, CA 92122, Tel: 619-558-1057. Wainwright Instruments GmbH, Widdersberger Strasse 14, DW-8138 Andechs-Frieding, Germany. Tel: +49-8152-2245, Fax: +49-8152-5174.

Page 13.6: Second column, line 16: change gm5 and C5 to gm2 and C4.

Figure 13.7: C4 in the "Noiseless" column should be $159 \times 10^{-9} F$.

Page 13.10: Second column, line 17: Change "By" to "because".

Page 13.28: Change last sentence to read: "The complete list of all 300 models on the "Release F, 4/92 version of the diskette is shown in Figure 13.30.

Figure 13.30: Replace with Release F listing which contains 300 macromodels.
(Figure attached to errata sheet).

Index, Page 19: Add "monolithic thermocouple amplifiers, II.68-69"

Analog Devices Parts Index, Page 22: Add: AD594, AD595, AD596, AD597, pp. II.68-69.

(Put at end of Section II)

**MONOLITHIC THERMOCOUPLE AMPLIFIERS WITH COLD JUNCTION COMPENSATION:
THE AD594/AD595/AD596/AD597**

The AD594/AD595 is a complete instrumentation amplifier and thermocouple cold junction compensator on a monolithic chip. It combines an ice point reference with a precalibrated amplifier to produce a high level ($10\text{mV}^{\circ}\text{C}$) output directly from a thermocouple signal. Pin-strapping options allow it to be used as a linear amplifier-compensator or as a switched output set-point controller using either fixed or remote set-point control. It can be used to amplify its compensation voltage directly, thereby converting it into a stand-alone Celsius transducer with a low-impedance output voltage.

The AD594/AD595 includes a thermocouple failure alarm that indicates if one or both thermocouple leads become open. The alarm output has a flexible format which includes TTL drive capability.

The AD594/AD595 can be powered from a single ended supply (including +5V) and by including a negative supply, temperatures below 0°C can be measured. To minimize self-heating, an unloaded AD594/AD595 will typically operate with a total supply current of $160\mu\text{A}$, but is also capable of delivering in excess of $\pm 5\text{mA}$ to a load.

The AD594 is precalibrated by laser wafer trimming to match the characteristic of type J (iron-constantan) thermocouples, and the AD595 is laser trimmed for type K (chromel-alumel) inputs. The temperature transducer voltages and gain control resistors are available at the package pins so that the circuit can be recalibrated for other thermocouple types by the addition of two or three resistors. These terminals also allow more precise calibration for both thermocouple and thermometer applications. The AD594/AD595 is available in two performance grades. The C and the A versions have calibration accuracies of $\pm 1^{\circ}\text{C}$ and $\pm 3^{\circ}\text{C}$, respectively. Both are designed to be used from 0 to $+50^{\circ}\text{C}$, and are available in 14-pin, hermetically sealed, sidebrazed ceramic DIPs as well as low cost cerdip packages.

The AD596/AD597 is a monolithic temperature set-point controller which has been optimized for use at elevated temperatures such as those found in oven control applications. The device cold junction compensates and amplifies a type J or K thermocouple input to derive an internal signal proportional to temperature. The AD596/AD597 can be configured to provide a voltage output ($10\text{mV}^{\circ}\text{C}$) directly from a type J or K thermocouple signal. The device is packaged in a reliability qualified, cost effective 10-pin metal can and is trimmed to operate over an ambient temperature range from $+25^{\circ}\text{C}$ to $+100^{\circ}\text{C}$.

Operation over an extended ambient temperature range is possible with slightly reduced accuracy. The AD596 will amplify thermocouple signals covering the entire -200°C to $+760^{\circ}\text{C}$ temperature range recommended for type J thermocouples while the AD597 can accommodate -200°C to $+1250^{\circ}\text{C}$ type K inputs. The AD596/AD597 has a calibration accuracy of $\pm 4^{\circ}\text{C}$ at an ambient temperature of 60°C and an ambient temperature stability specification of $0.05^{\circ}\text{C}/^{\circ}\text{C}$ from $+25^{\circ}\text{C}$ to $+100^{\circ}\text{C}$.

BiFET OP AMP SIMPLIFIED INPUT CIRCUIT

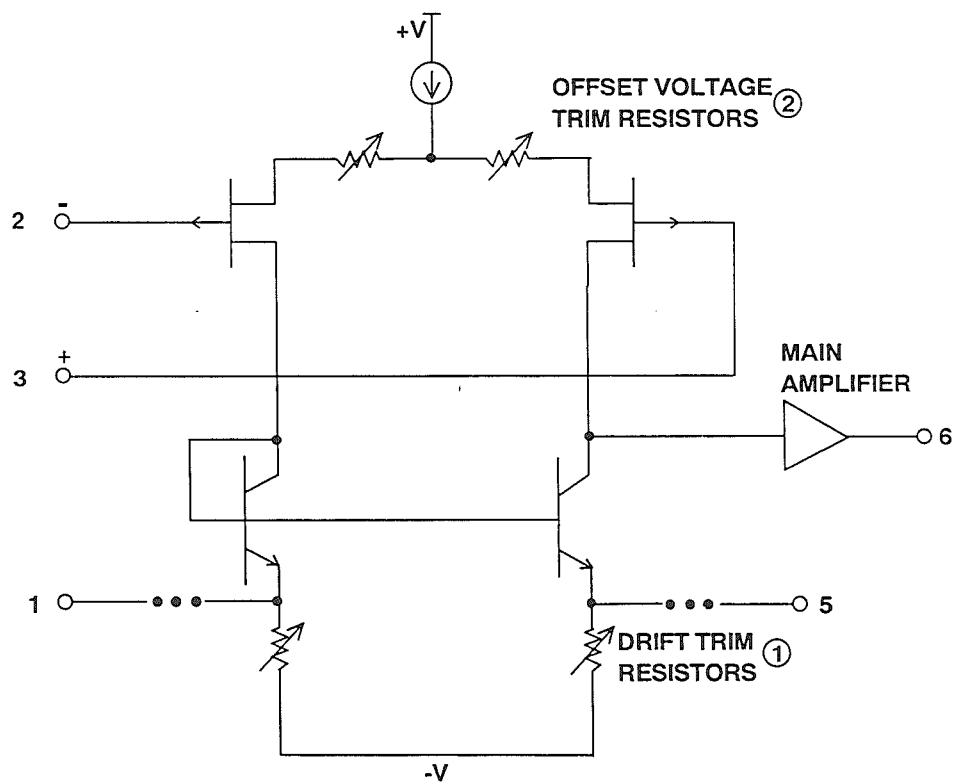


Figure 3.16

OFFSET VOLTAGE NULLING USING INVERTING INPUT

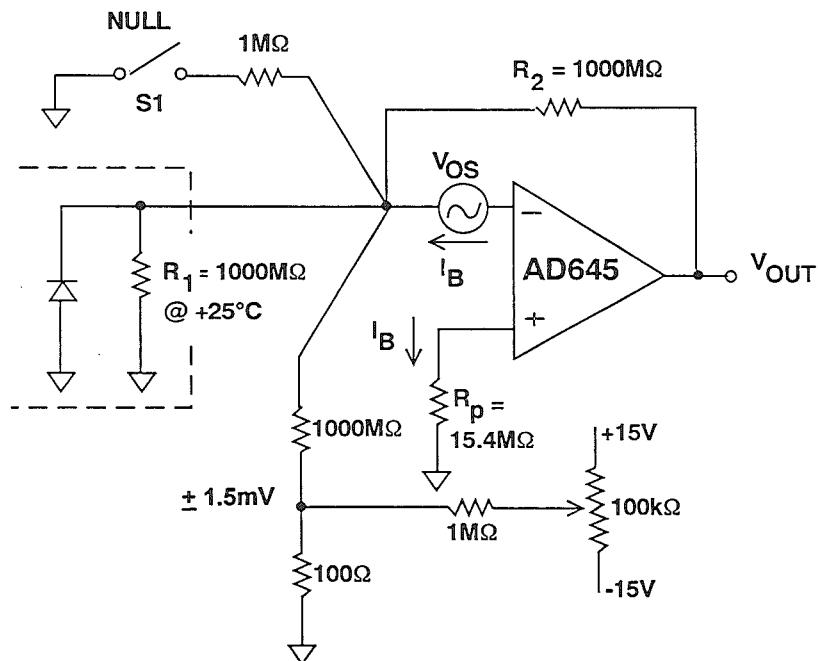


Figure 3.18

OFFSET VOLTAGE NULLING USING NON-INVERTING INPUT

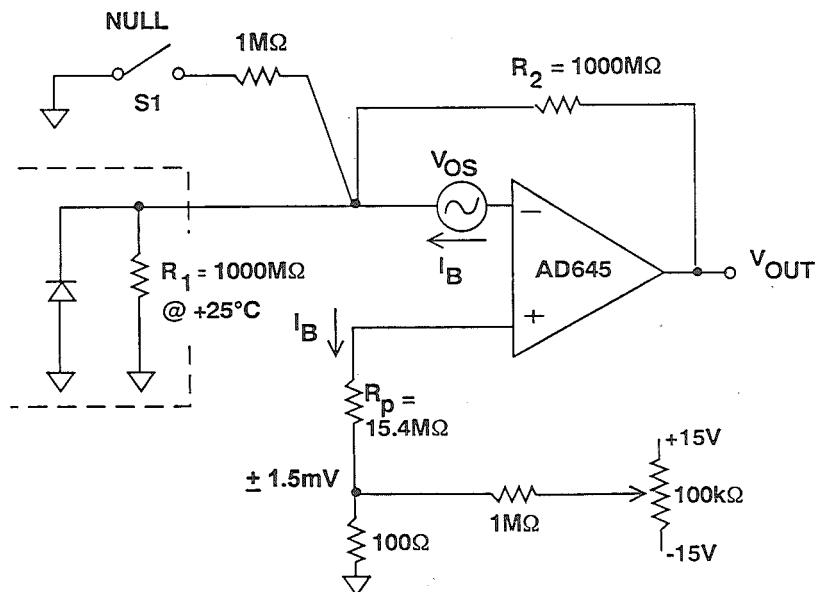


Figure 3.19

FINAL DC DESIGN FOR PHOTODIODE PREAMP

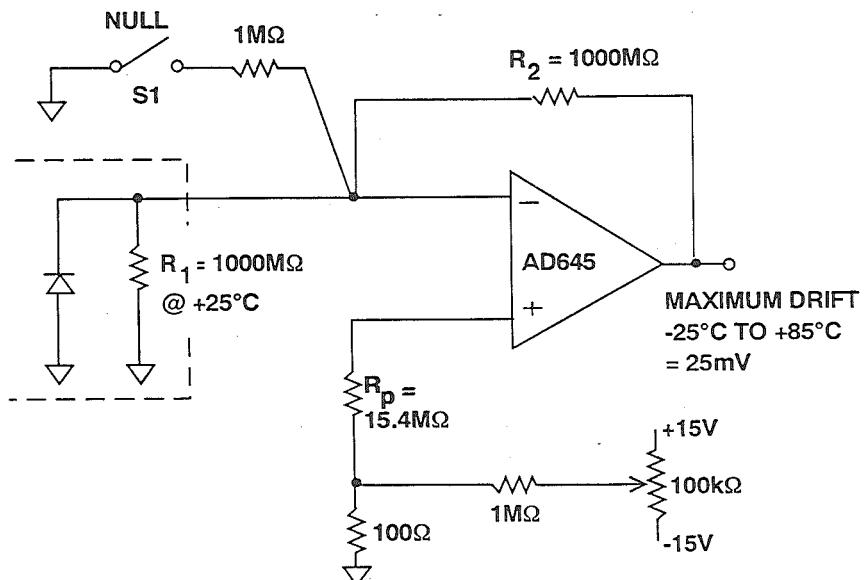


Figure 3.21

REACTIVE PORTION OF PHOTODIODE CIRCUIT

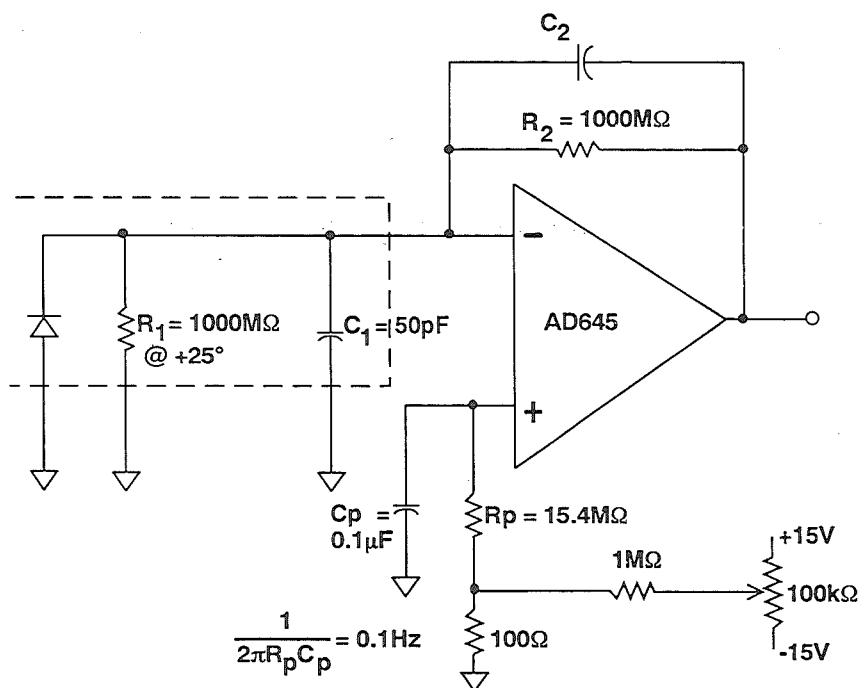


Figure 3.24

OPTIMIZED PHOTODIODE PREAMP

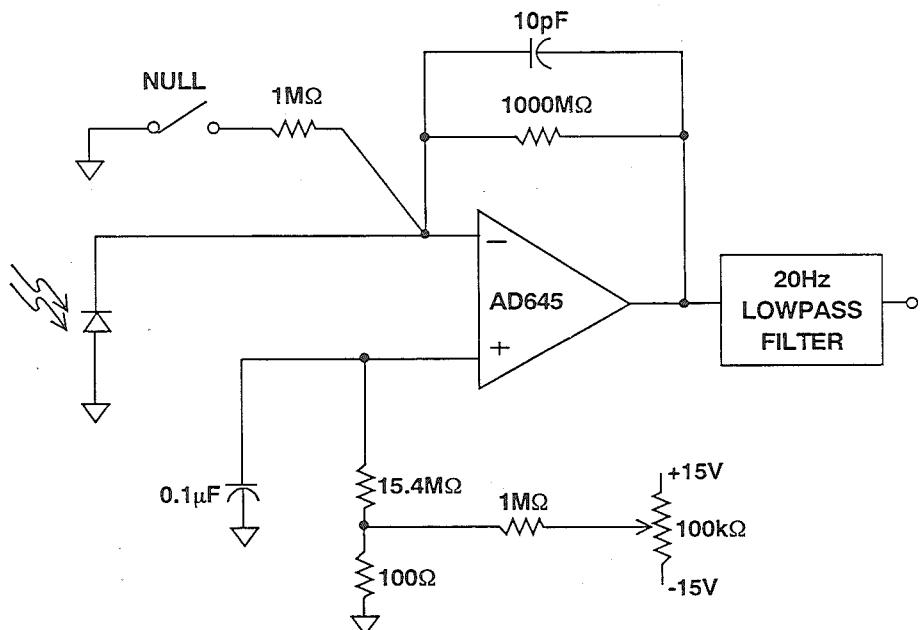


Figure 3.37

DIFFERENTIAL DRIVER (ONE CHANNEL) FOR AD1879 SIGMA-DELTA AUDIO ADC

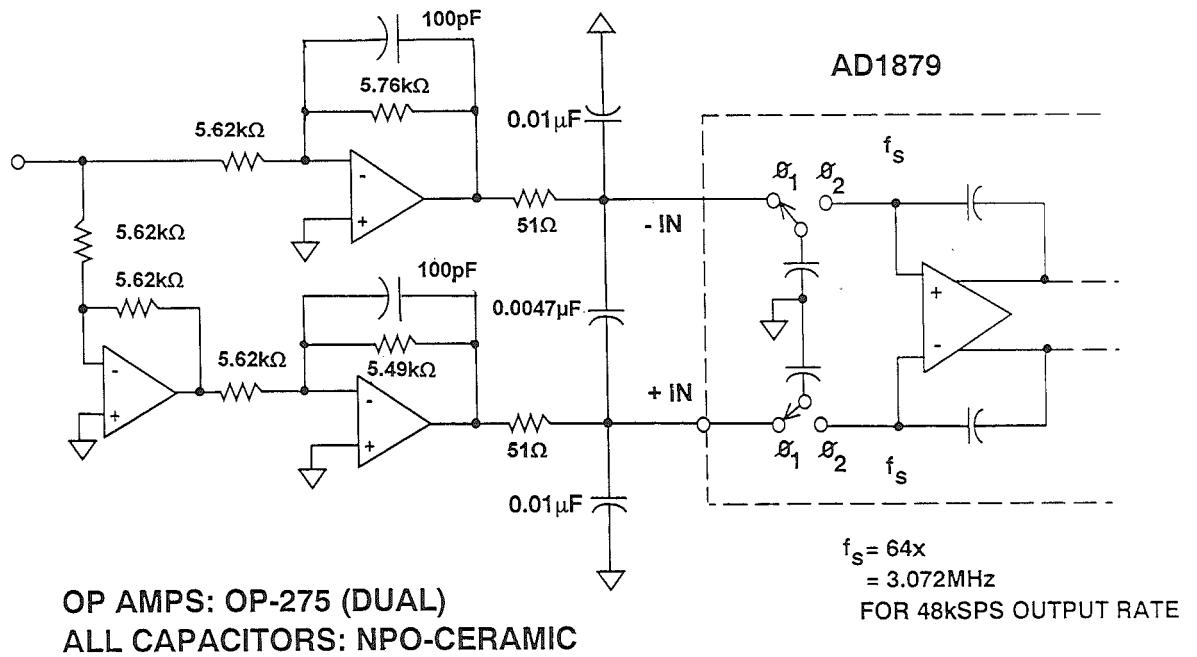


Figure 7.85

ADSpice Release F, 4/92

AD624	AD734B *	AD848	OP249E	OP42G
AD624A	AD734S *	AD848A	OP249F	OP43
AD624B	AD743 *(N)	AD848J	OP249G	OP43A
AD624C	AD743A *(N)	AD848S	OP260	OP43B
AD624S	AD743B *(N)	AD9617	OP27 *(N)	OP43E
AD630 *	AD743J *(N)	AD9618	OP27A *(N)	OP43F
AD630A *	AD743K *(N)	AD9630	OP27B *(N)	OP43G
AD630B *	AD743S *(N)	AMP01	OP27C *(N)	OP44
AD630J *	AD744	AMP02	OP27E *(N)	OP470
AD630K *	AD744A	MAT02	OP27F *(N)	OP482 *
AD630S *	AD744B	MAT03	OP27G *(N)	OP482G *
AD645 *(N)	AD744C	MAT04	OP275 *(N)	OP490
AD645A *(N)	AD744J	OP160	OP275G *(N)	OP490A
AD645B *(N)	AD744K	OP160A	OP282 *	OP490E
AD645J *(N)	AD744S	OP160F	OP282G *	OP490F
AD645K *(N)	AD744T	OP160G	OP290	OP490G
AD645S *(N)	AD745 *(N)	OP177 *(N)	OP290A	OP497
AD704	AD745A *(N)	OP177A *(N)	OP290E	OP497A
AD704A	AD745B *(N)	OP177B *(N)	OP290F	OP497B
AD704B	AD745J *(N)	OP177E *(N)	OP290G	OP497C
AD704J	AD745K *(N)	OP177F *(N)	OP297	OP497F
AD704K	AD745S *(N)	OP177G *(N)	OP297A	OP497G
AD704T	AD746	OP200	OP297E	OP61
AD705	AD746A	OP200A	OP297F	OP64
AD705A	AD746B	OP200E	OP297G	OP77 *(N)
AD705B	AD746J	OP200F	OP37 *(N)	OP77A *(N)
AD705J	AD746S	OP200G	OP37A *(N)	OP77B *(N)
AD705K	AD811	OP20	OP37B *(N)	OP77E *(N)
AD705T	AD829	OP20B	OP37C *(N)	OP77F *(N)
AD706	AD829A	OP20C	OP37E *(N)	OP77G *(N)
AD706A	AD829J	OP20F	OP37F *(N)	OP90
AD706B	AD829S	OP20G	OP37G *(N)	OP90A
AD706J	AD840	OP20H	OP400	OP90E
AD706K	AD840J	OP215	OP400A	OP90F
AD706T	AD840K	OP215A	OP400E	OP90G
AD711	AD840S	OP215B	OP400F	OP97
AD711A	AD843 *	OP215C	OP400G	OP97A *
AD711B	AD843A *	OP215E	OP400H	OP97E *
AD711C	AD843B *	OP215F	OP41	OP97F *
AD711J	AD843J *	OP215G	OP41A	PM1012
AD711K	AD843K *	OP21	OP41B	REF01 *(N)
AD711S	AD843S *	OP21A	OP41E	REF01A *(N)
AD711T	AD844	OP21E	OP41F	REF01C *(N)
AD712 *(N)	AD844A	OP21F	OP41G	REF01E *(N)
AD712A *(N)	AD844B	OP21G	OP420	REF01H *(N)
AD712B *(N)	AD844S	OP21H	OP420B	REF02 *(N)
AD712C *(N)	AD845	OP220	OP420C	REF02A *(N)
AD712J *(N)	AD845A	OP220A	OP420F	REF02C *(N)
AD712K *(N)	AD845B	OP220C	OP420G	REF02D *(N)
AD712S *(N)	AD845J	OP220E	OP420H	REF02E *(N)
AD712T *(N)	AD845K	OP220F	OP421	REF02H *(N)
AD713	AD845S	OP220G	OP421B	REF05 *(N)
AD713A	AD846	OP221	OP421C	REF05A *(N)
AD713B	AD846A	OP221A	OP421F	REF05B *(N)
AD713J	AD846B	OP221B	OP421G	REF10 *(N)
AD713K	AD846S	OP221C	OP421H	REF10A *(N)
AD713S	AD847	OP221E	OP42	REF10B *(N)
AD713T	AD847A	OP221G	OP42A	SSM2131
AD734	AD847J	OP249	OP42E	SSM2210
AD734A *	AD847S	OP249A	OP42F	SSM2220

* Indicates new model since release E, 10/91

(N) Indicates noise model

Figure 13.30

